

# **Dual P-Channel 350V Enhancement Mode MOSFETs**

## **General Features**

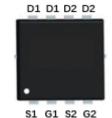
- Proprietary Advanced Planar Technology
- Rugged Polysilicon Gate Cell Structure
- Fast Switching Speed

$\triangleright$	RoHS Compliant	0001	20	
	Halogen-free available			
	_		PDFN3333	

# **Applications**

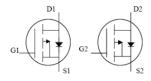
- High Efficiency SMPS
- Adaptor/Charger
- Active PFC

RDS(ON) (Max.)	$I_D$
30 Ω	-0.5A



 $BV_{DSS}$ 

-350V



# **Ordering Information**

Part Number	Part Number Package Ma		ng Remark	
FTF30P35D	PDFN3333	30P35D	Halogen Free	

# **Absolute Maximum Ratings**

T<sub>A</sub>=25°C unless otherwise specified

Symbol	Parameter	FTF30P35D	Unit	
$V_{\mathrm{DSS}}$	Drain-to-Source Voltage <sup>[1]</sup>	-350	V	
$I_D$	Continuous Drain Current	-0.5		
$I_{DM}$	Pulsed Drain Current <sup>[2]</sup>	-2	A	
$P_D$	Power Dissipation	16	W	
$V_{GS}$	Gate-to-Source Voltage	±20	V	
$T_{L}$	Soldering Temperature Distance of 1.6mm from case for 10 seconds	300	°C	
T <sub>J</sub> and T <sub>STG</sub>	Operating and Storage Temperature Range	-55 to 150		

Caution: Stresses greater than those listed in the "Absolute Maximum Ratings" may cause permanent damage to the device.

# **Thermal Characteristics**

Symbol	Parameter	FTF30P35D	Unit
$R_{ heta JA}$	Thermal Resistance, Junction-to-Ambient	34	K/W



## **Electrical Characteristics**

## **OFF** Characteristics

 $T_A = 25$ °C unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Unit	<b>Test Conditions</b>
BV <sub>DSS</sub>	Drain-to-Source Breakdown Voltage	-350	1		V	$V_{GS}$ =0V, $I_{D}$ =-250 $\mu$ A
	Drain-to-Source Leakage Current			-1	μΑ	$V_{DS}$ =-350V, $V_{GS}$ = 0V
$I_{DSS}$				-100	μΑ	$V_{DS}$ =-350V, $V_{GS}$ = 0V $T_J$ =125 °C
Ţ	Gate-to-Source Leakage Current			20	μA	$V_{GS} = +20V, V_{DS} = 0V$
IGSS				-20		$V_{GS}$ =-20V, $V_{DS}$ =0V

#### **ON** Characteristics

#### $T_A$ =25 °C unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Conditions
R <sub>DS(ON)</sub>	Static Drain-to-Source On-Resistance		18	30	Ω	$V_{GS}$ =-10V, $I_D$ =-200mA <sup>[3]</sup>
V <sub>GS(TH)</sub>	Gate Threshold Voltage	-1		-3	V	$V_{GD} = 0V, I_D = -250 \mu A$

# **Dynamic Characteristics**

#### Essentially independent of operating temperature

Symbol	Parameter	Min.	Тур.	Max.	Unit	<b>Test Conditions</b>
C <sub>ISS</sub>	Input Capacitance		43.39			$V_{GS}=0V$
Coss	Oput Capacitance		6.94		pF	$V_{DS}=-25V$
$C_{RSS}$	Reverse Transfer Capacitance		0.84			$f=1.0MH_Z$
t <sub>d(ON)</sub>	Turn-on Delay Time		12			$V_{GS} = -10V \sim 0V$ $V_{DD} = -25V, I_D = -80mA$ $R_G = 25Ohm$
t <sub>rise</sub>	Rise Time		60		ns	
$t_{d(OFF)}$	Turn-off Delay Time		136			
t <sub>fall</sub>	Fall Time		320			

# **Source-Drain Diode Characteristics**

#### T<sub>A</sub>=25°C unless otherwise specified

Symbol	Parameter	Min	Тур.	Max.	Units	<b>Test Conditions</b>
$V_{\mathrm{SD}}$	Diode Forward Voltage			-1.8	V	$I_{SD} = -200 \text{ mA}, V_{GS} = 0 \text{ V}$

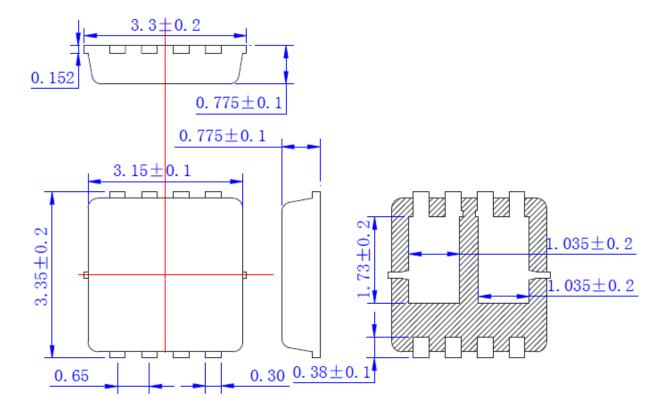
#### NOTE:

- [1]  $T_J = +25^{\circ}C$  to  $+150^{\circ}C$
- [2] Repetitive rating, pulse width limited by maximum junction temperature.
- [3] Pulse width \( 380 \mu s; \) duty cycle \( \le 2 \%.



# **Package Dimensions**

# **PDFN3333**





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